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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : TBD
Applicant : Yuichiro Sasaki et al.
Filed : Herewith
Title : "BEAM CURRENT MEASURING APPARATUS AND BEAM CURRENT MEASURING METHOD USING THE SAME"

Confirmation No. : TBD
TC/A.U. : TBD
Examiner : TBD

International App. No. : PCT/JP2004/003319
International Flg. Date : March 12, 2004

Customer No. : 052054
Docket No. : 38771

INFORMATION DISCLOSURE STATEMENT

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Alexandria, Va. 22313-1450

Sir/Madam:

In accordance with Rule 56, applicants are aware of the publications listed in the International Search Report (ISR, copy enclosed) and in the enclosed copy of Patent Office Form 1449. Copies of the publications cited in the International Search Report are not enclosed as they were previously forwarded by the International Bureau.

If there are any fees required by this communication, please charge such fees to our Deposit Account No. 16-0820, Order No. 38771

Respectfully submitted,

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U.S. PATENT DOCUMENTS

| Examiner Initial | | Document No. | Date | Name | Class | Subclass | Filing Date If Appropriate |
|------------------|---|--------------|------|------|-------|----------|----------------------------|
| | A | | | | | | |
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FOREIGN PATENT DOCUMENTS

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|--|---|--------------|---------|---------|-------|----------|--------------|
| | L | 2001-91611 | 04/2001 | JAPAN | | | Cited on ISR |
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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